

Search Notes

Application/Control No.

10/664,662

Examiner

Huy D. Nguyen

Applicant(s)/Patent under
Reexamination

ISHIKAWA ET AL.

Art Unit

2617

SEARCHED			
Class	Subclass	Date	Examiner
455	423	2/8/2006	HN
	436		
	437		
	442		
	434		
	439		
	502		
	127.1		
	127.5		
Updated	search	10/6/2006	HN
Updated	search	3/17/2007	HN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	2/8/2006	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	10/6/2006	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	3/17/2007	HN